

UNISONIC TECHNOLOGIES CO., LTD

3N40 **Preliminary Power MOSFET**

TO-220F

TO-252

TO-252D

3A, 400V N-CHANNEL **POWER MOSFET**

DESCRIPTION

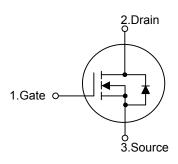
The UTC 3N40 is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology specializes in allowing a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

The UTC 3N40 is universally applied in electronic lamp ballast based on half bridge topology and high efficient switched mode power supply.

FEATURES

- * $R_{DS(ON)}$ <2.0 Ω @ V_{GS} =10V, I_D =1.5A
- * High switching speed
- * 100% avalanche tested

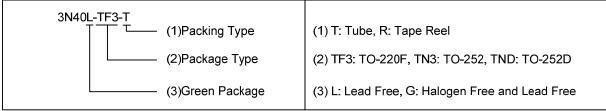
SYMBOL



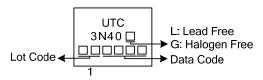
ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
3N40L-TF3-T	3N40G-TF3-T	TO-220F	G	D	S	Tube	
3N40L-TN3-R	3N40G-TN3-R	TO-252	G	D	S	Tape Reel	
3N40L-TND-R	3N40G-TND-R	TO-252D	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING



www.unisonic.com.tw 1 of 6 QW-R502-553.d

■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	400	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous (T _C =25°C)	I _D	3	Α	
	Pulsed (Note 2)	I _{DM}	12	Α	
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	290	mJ	
	Repetitive (Note 2)	E _{AR}	3	mJ	
Power Dissipation	TO-220F		25	W	
	TO-252/TO-252D		50	W	
Derete chave 25°C	TO-220F	P _D	0.2	W/°C	
Derate above 25°C	TO-252/TO-252D		0.4	W/°C	
Junction Temperature		TJ	+150	°C	
Storage Temperature		T _{STG}	-55~+150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L=56mH, I_{AS} =3.0 A, V_{DD} =50V, R_{G} =25 Ω , Starting T_{J} = 25°C

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT	
Junction to Ambient	TO-220F	0	62.5	°C/W	
	TO-252/TO-252D	θ _{JA}	110		
Junction to Case	TO-220F	0	4.9	°C/W	
	TO-252/TO-252D	θ _{JC}	2.5	C/VV	

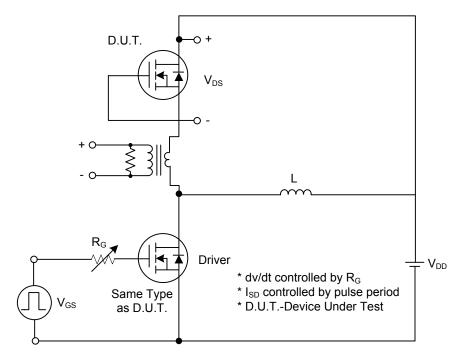
■ ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	400			V
Breakdown Voltage Temperature Coefficient		$\triangle BV_{DSS} / \triangle T_J$	Reference to 25°C, I _D =250µA		0.38		V/°C
Drain-Source Leakage Current		I _{DSS}	V _{DS} =400V, V _{GS} =0V			10	μΑ
Gate- Source Leakage Current	Forward	1	V_{GS} =+30V, V_{DS} =0V			+100	nA
	Reverse	I _{GSS}	V _{GS} =-30V, V _{DS} =0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$	2.0		4.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =1.5A			2.0	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C_{ISS}			445	545	pF
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		60	80	pF
Reverse Transfer Capacitance		C_{RSS}			13	16	pF
SWITCHING PARAMETERS							
Turn-ON Delay Time		$t_{D(ON)}$			40	50	ns
Rise Time		t_R	V_{GS} =10V, V_{DD} =30V, I_{D} =1A,		40	60	ns
Turn-OFF Delay Time		$t_{D(OFF)}$	R _G =25Ω (Note 1, 2)		100	120	ns
Fall-Time		t _F			60	80	ns
Total Gate Charge		Q_G	V _{DS} =100V, I _D =3A, I _G =3.3mA		40	60	nC
Gate to Source Charge		Q_GS	(Note 1, 2)		3.6		nC
Gate to Drain Charge		Q_GD	(Note 1, 2)		9.8		nC
SOURCE- DRAIN DIODE RATIN	NGS AND CH	HARACTERIST	rics				
Maximum Body-Diode Continuous Current		Is				3.0	Α
Maximum Body-Diode Pulsed Current		I _{SM}				12	Α
Drain-Source Diode Forward Voltage		V_{SD}	I _S =3A, V _{GS} =0V			1.5	V

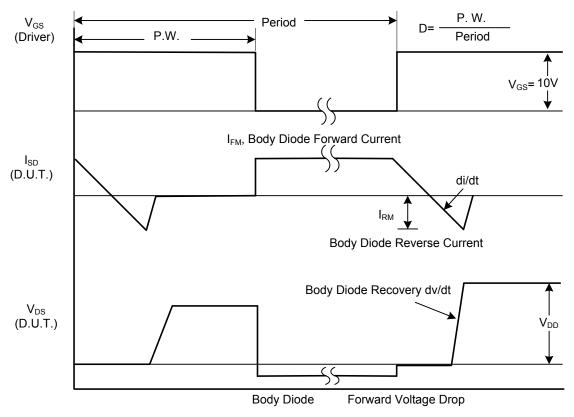
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%

^{2.} Essentially independent of operating temperature

■ TEST CIRCUITS AND WAVEFORMS

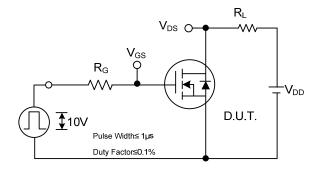


Peak Diode Recovery dv/dt Test Circuit

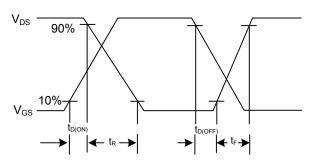


Peak Diode Recovery dv/dt Waveforms

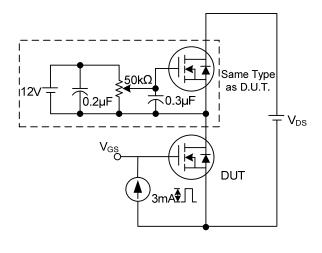
■ TEST CIRCUITS AND WAVEFORMS (Cont.)



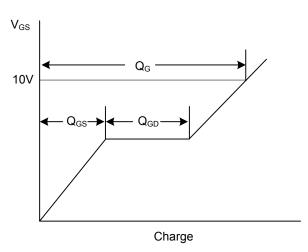
Switching Test Circuit



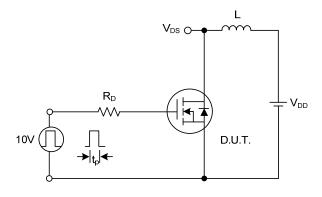
Switching Waveforms



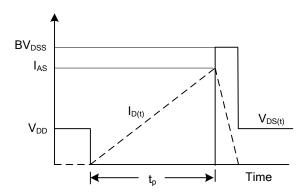
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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